

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner	John D. Lee	<i>John D. Lee</i>	Art Unit 2874	Page 1 of 1

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*	B	US-6,693,257	02-2004	Tanaka, Koichiro	219/121.76
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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